

Figure 1

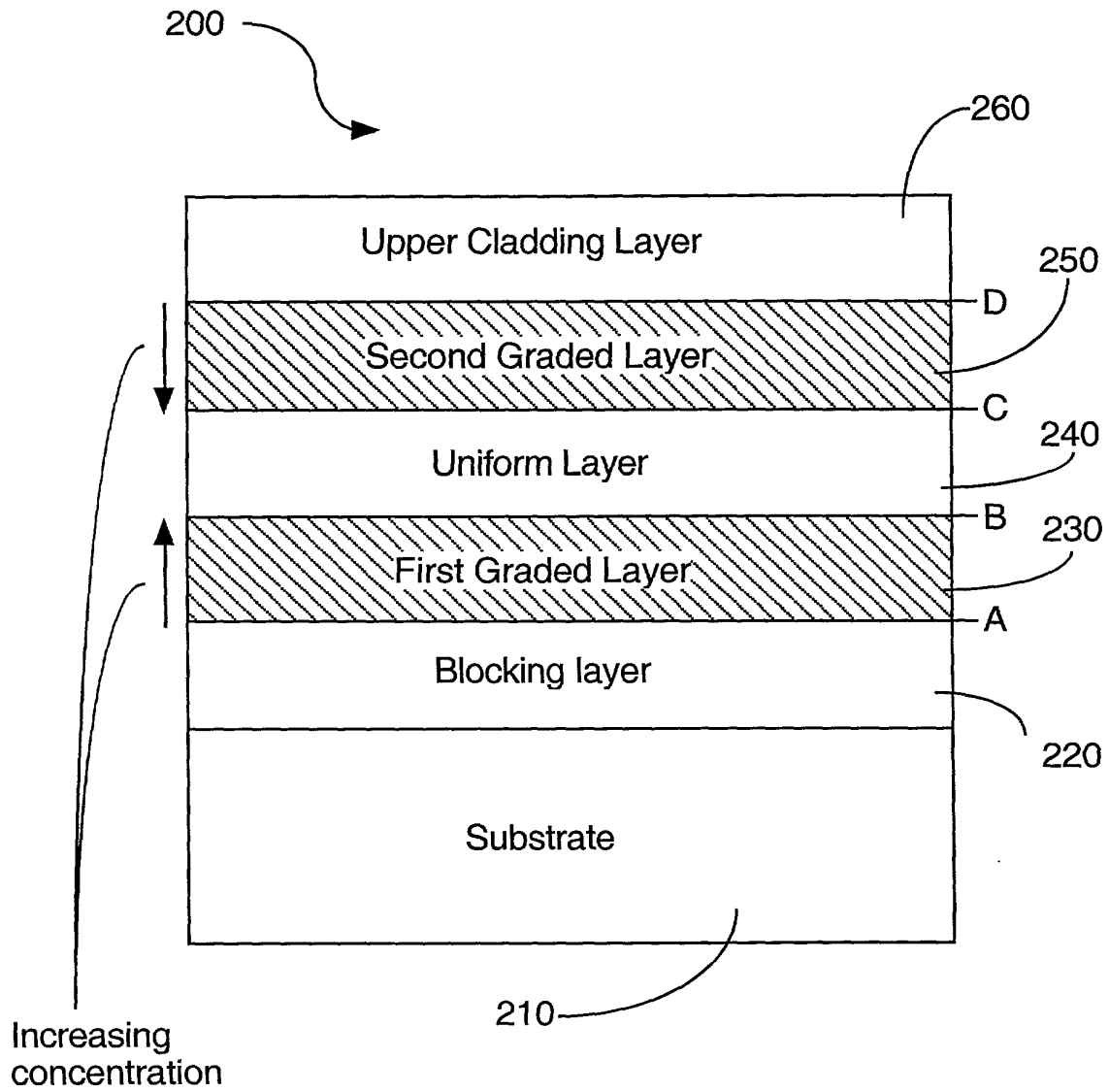


Figure 2A

X-Ray Photoelectron Deffraction Graph  
of a Si Substrate and SiGeC Layers with  
Different C Concentrations

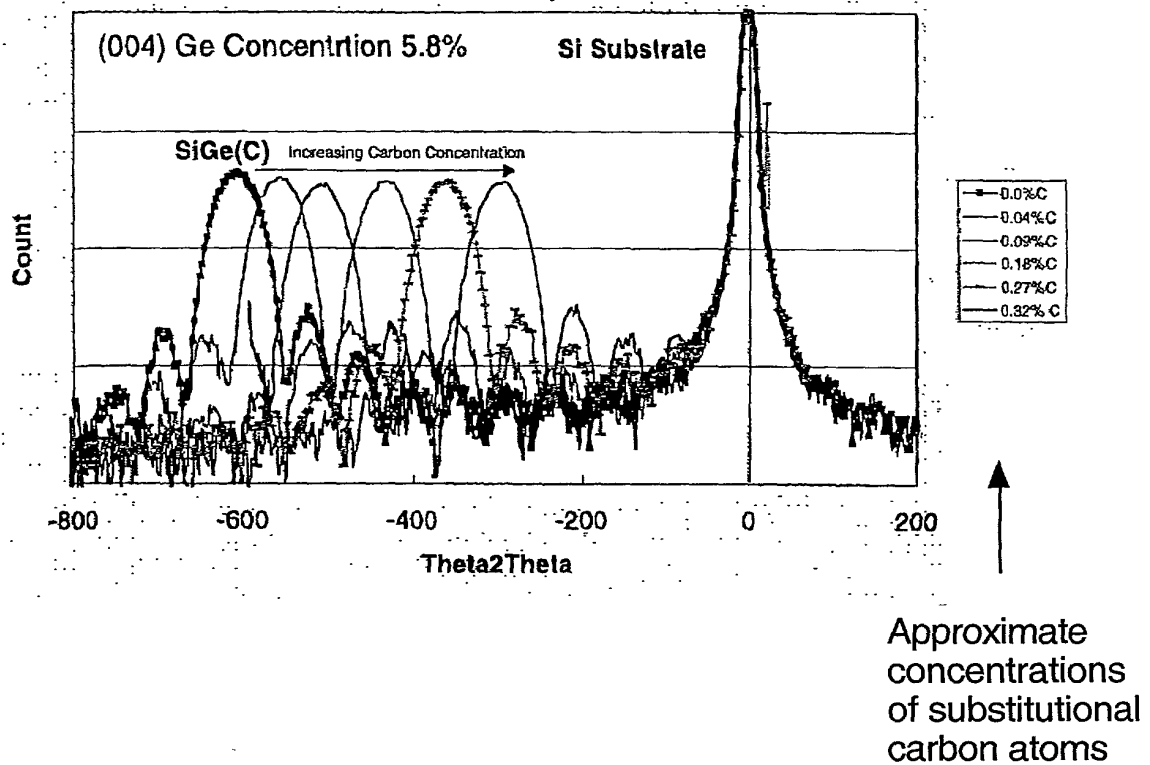


Figure 2B

4/18

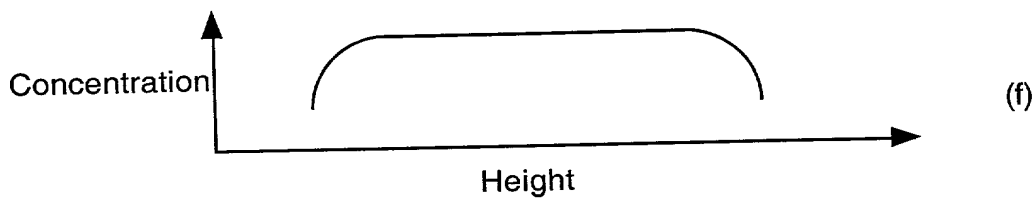
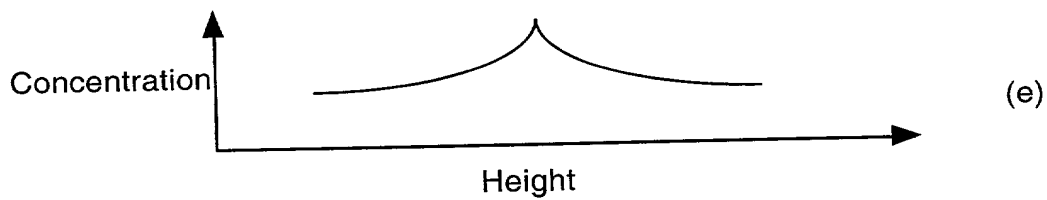
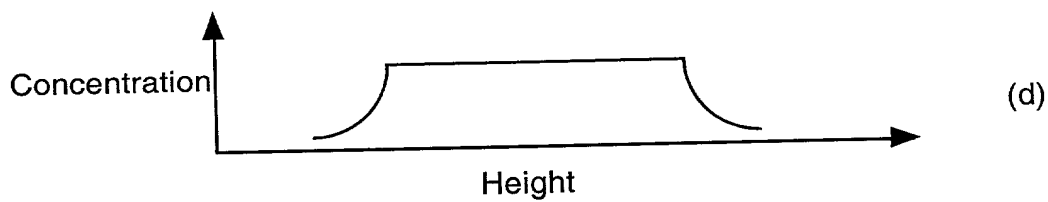
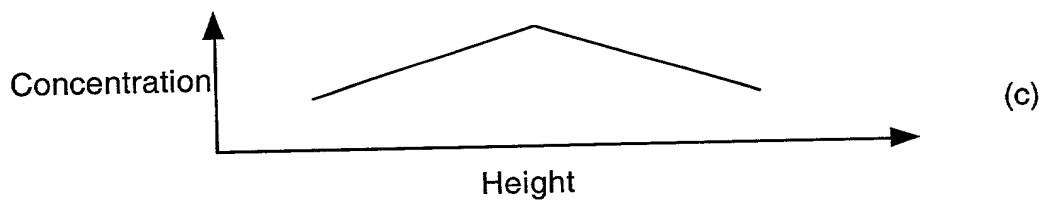
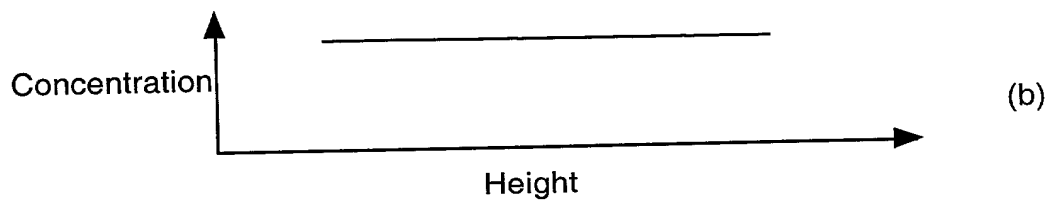
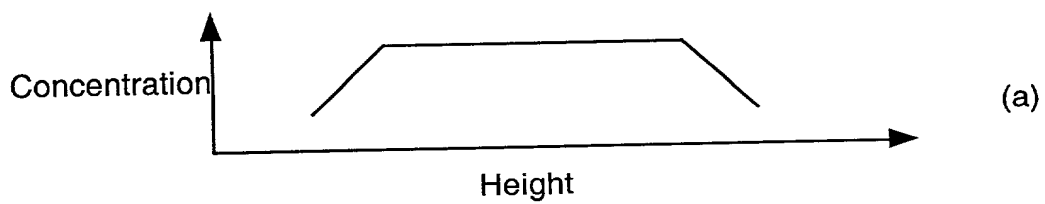


Figure 3

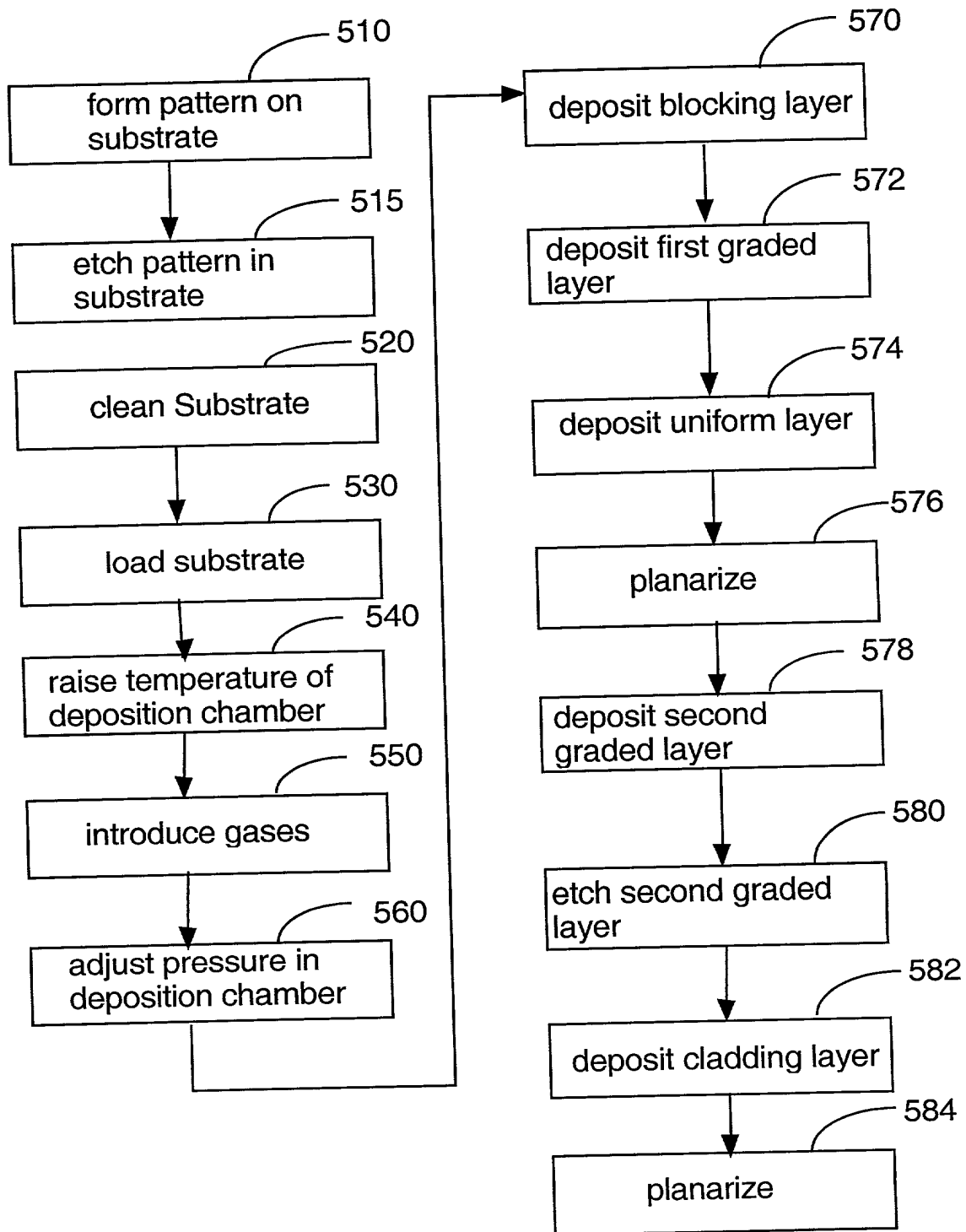
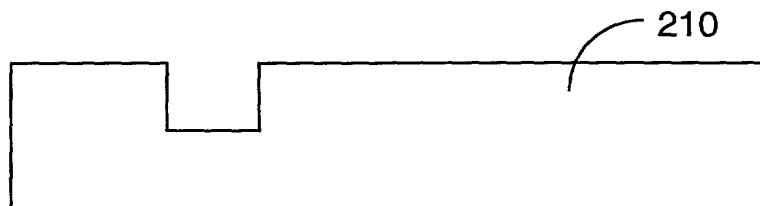
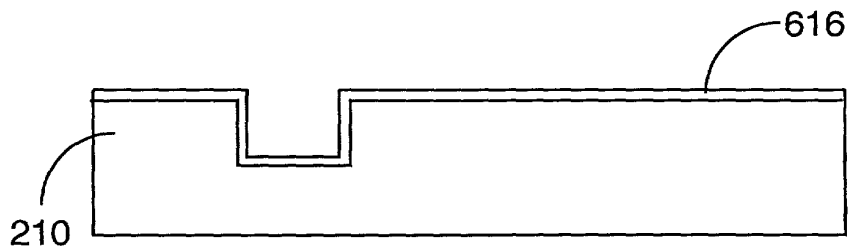


Figure 4

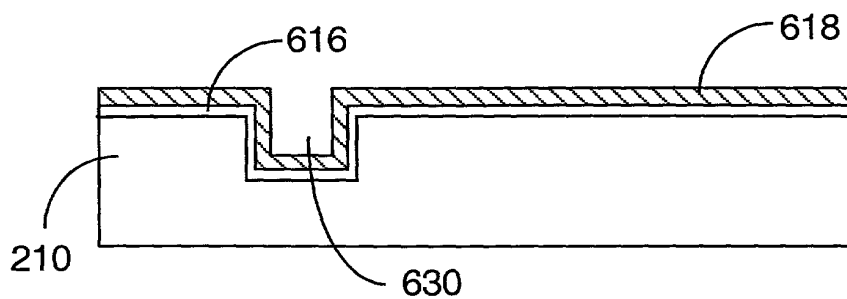
6/18



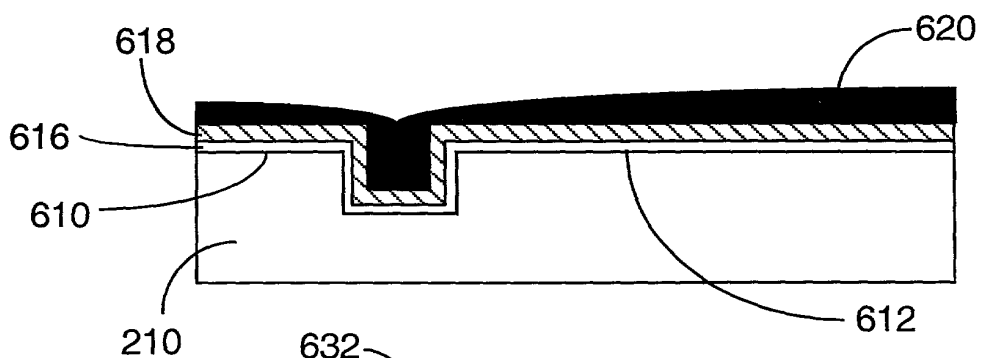
(a)



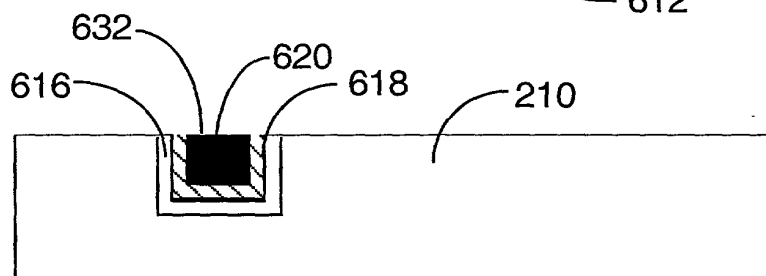
(b)



(c)



(d)



(e)

Figure 5

7/18

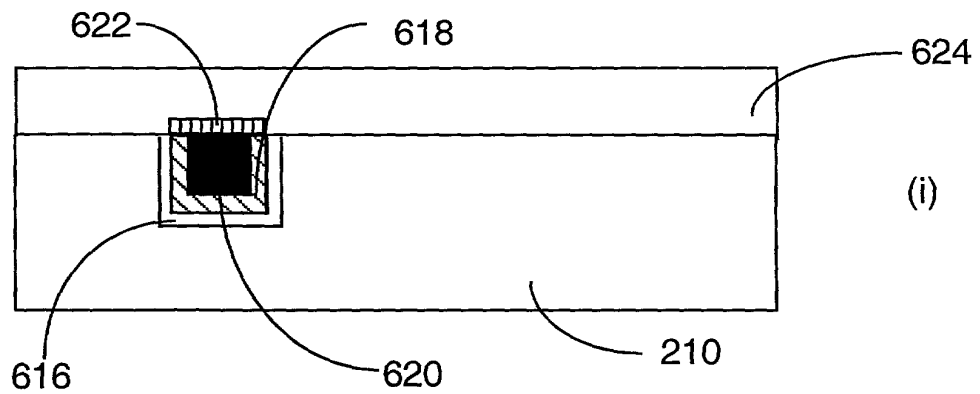
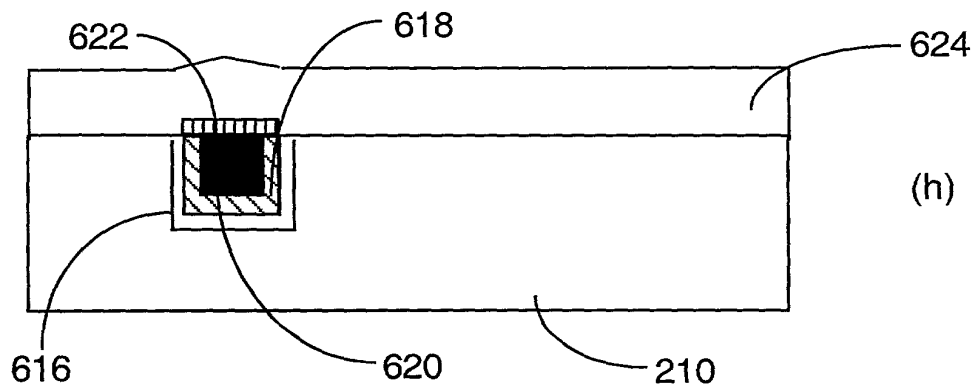
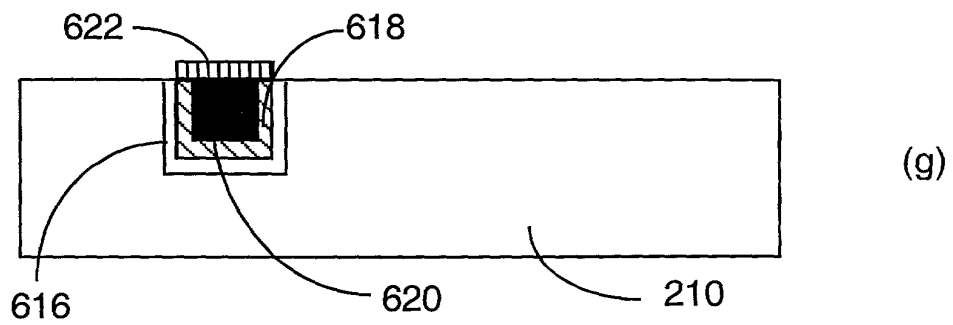
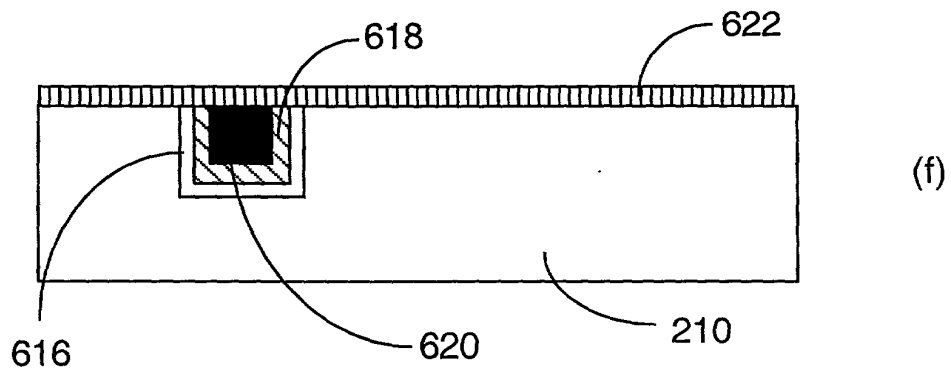
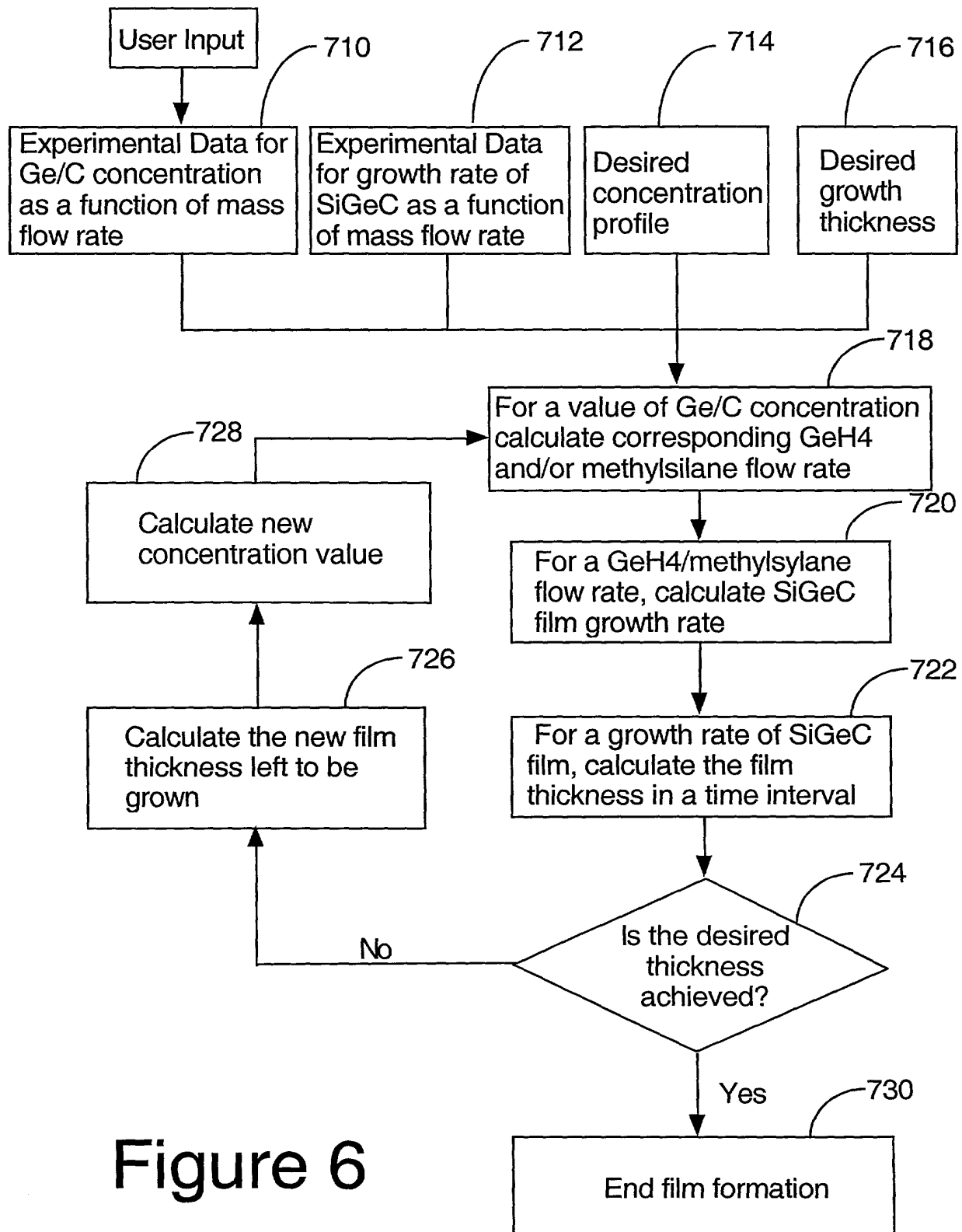


Figure 5

**Figure 6**



9/18

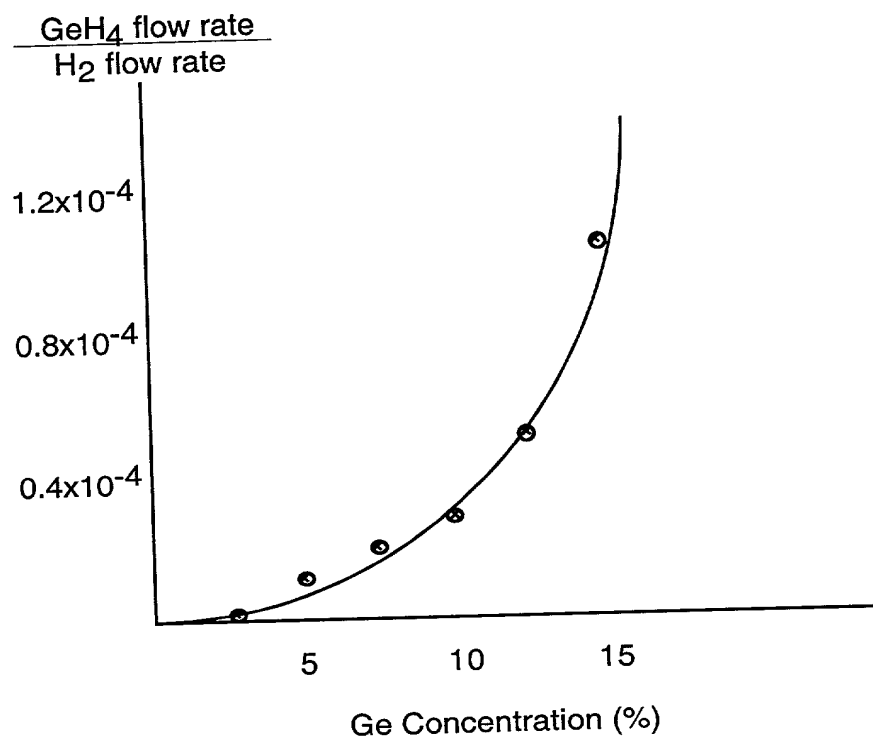


Figure 7A

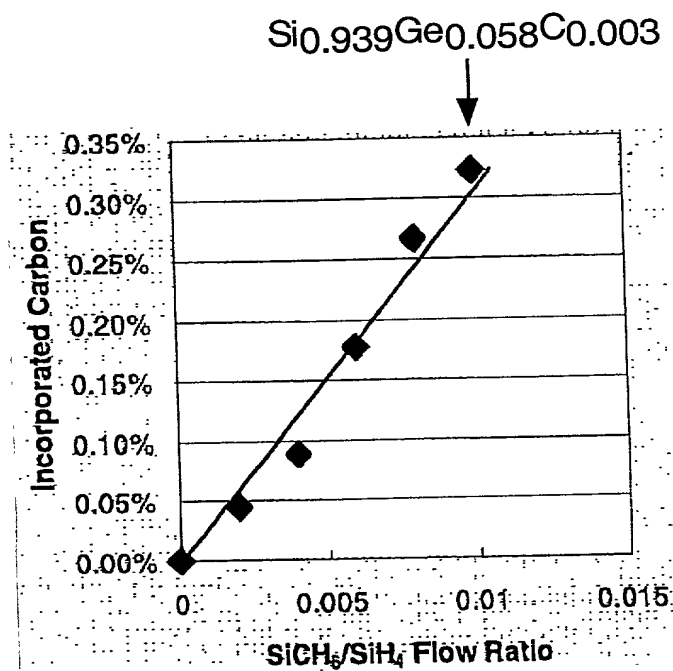


Figure 7B

10/18

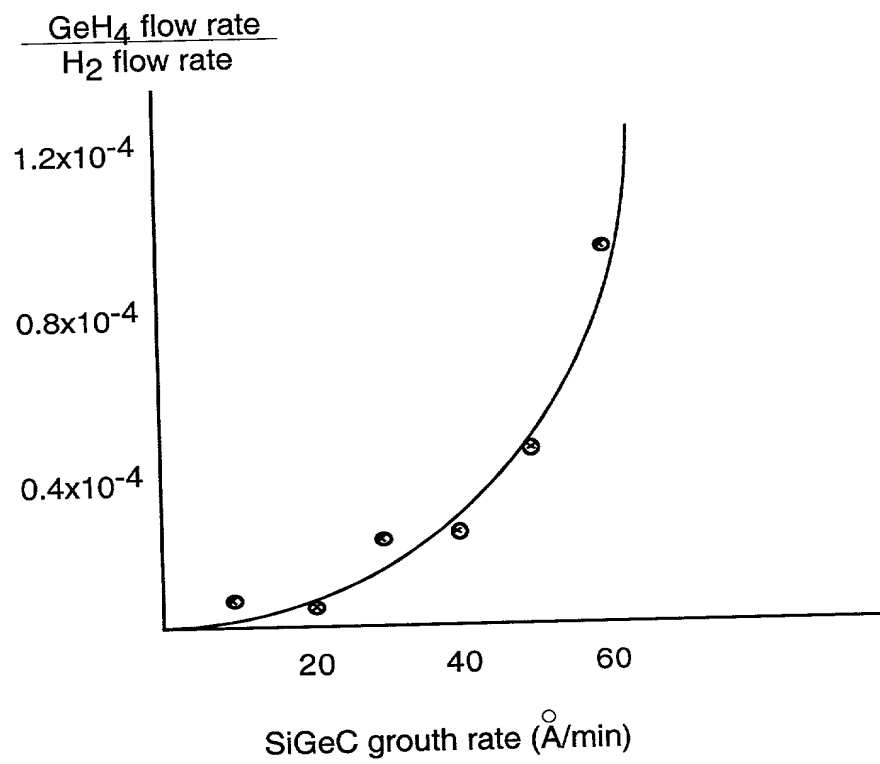
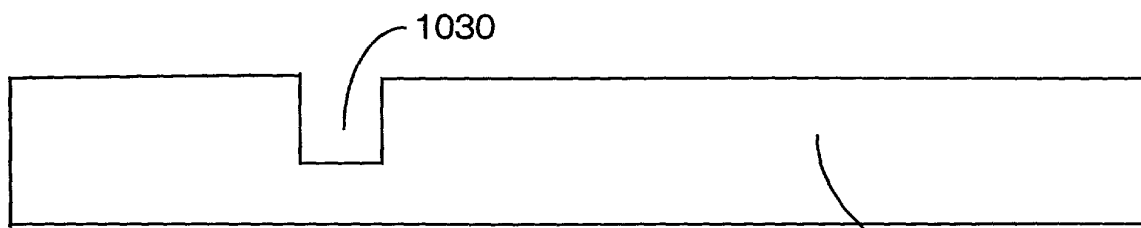
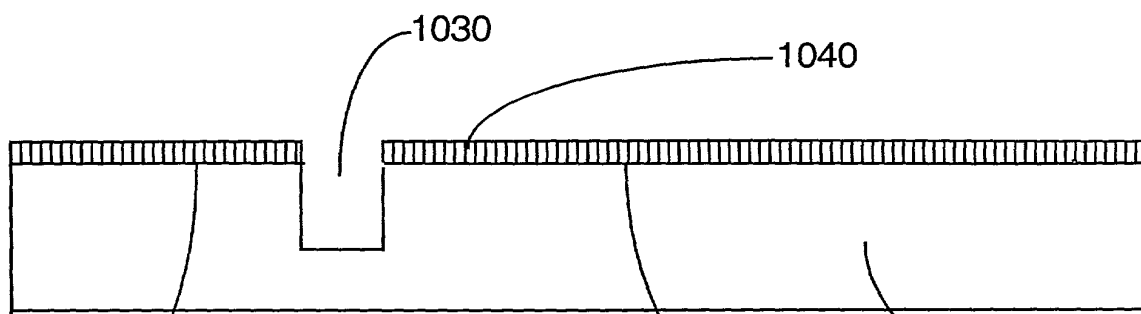


Figure 8

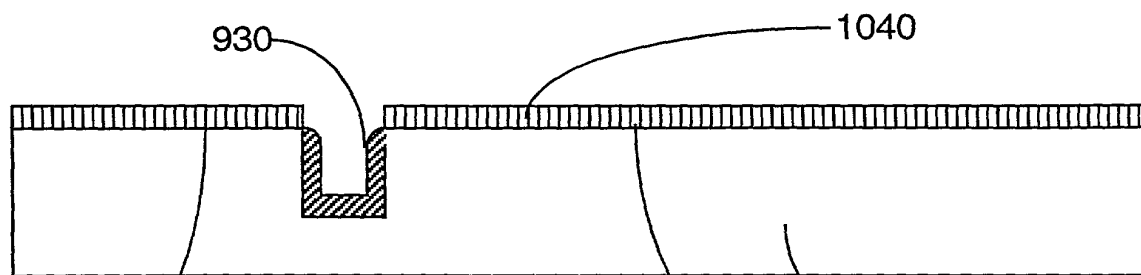
11/18



(a)



(b)



(c)

Figure 9

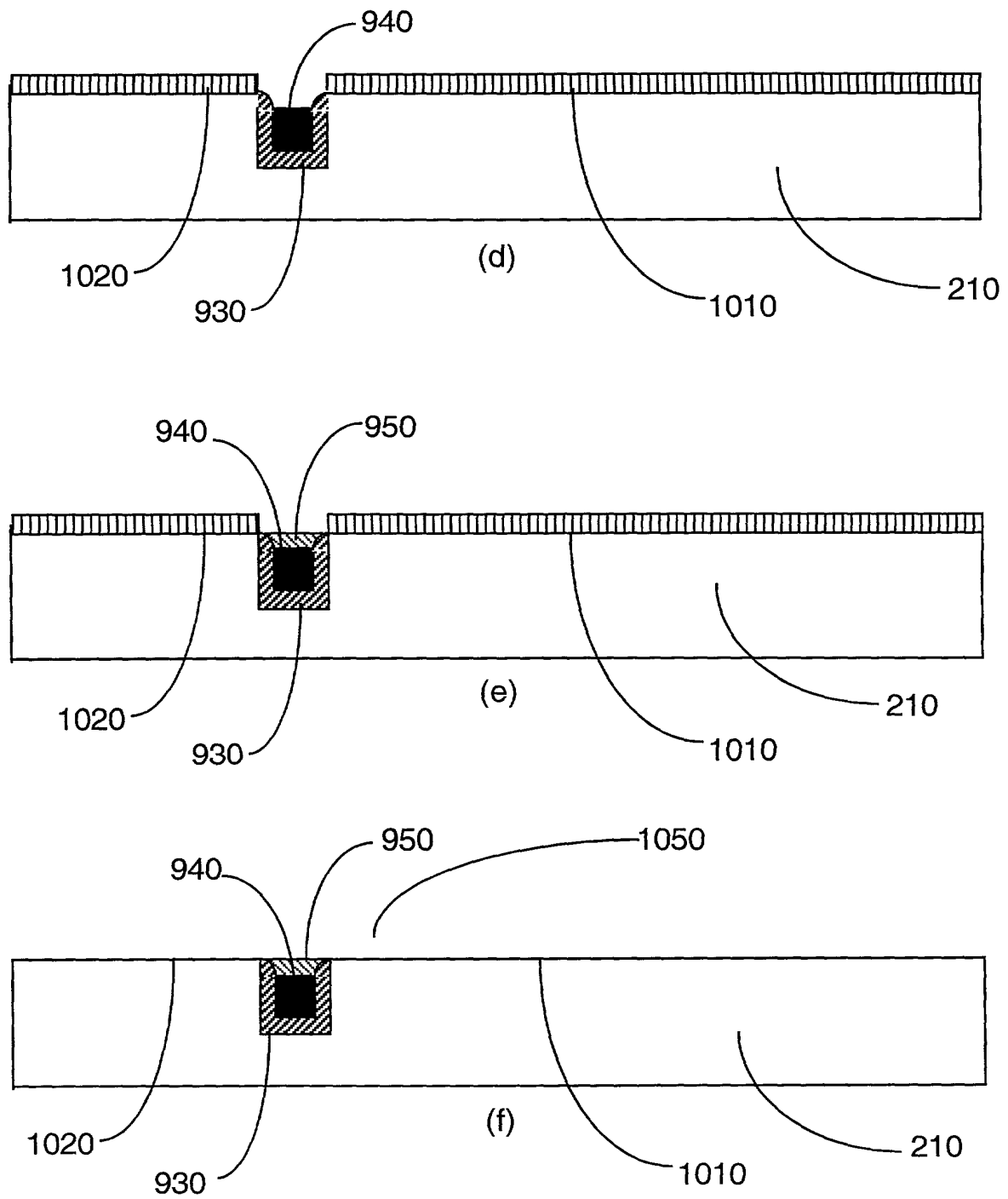


Figure 9

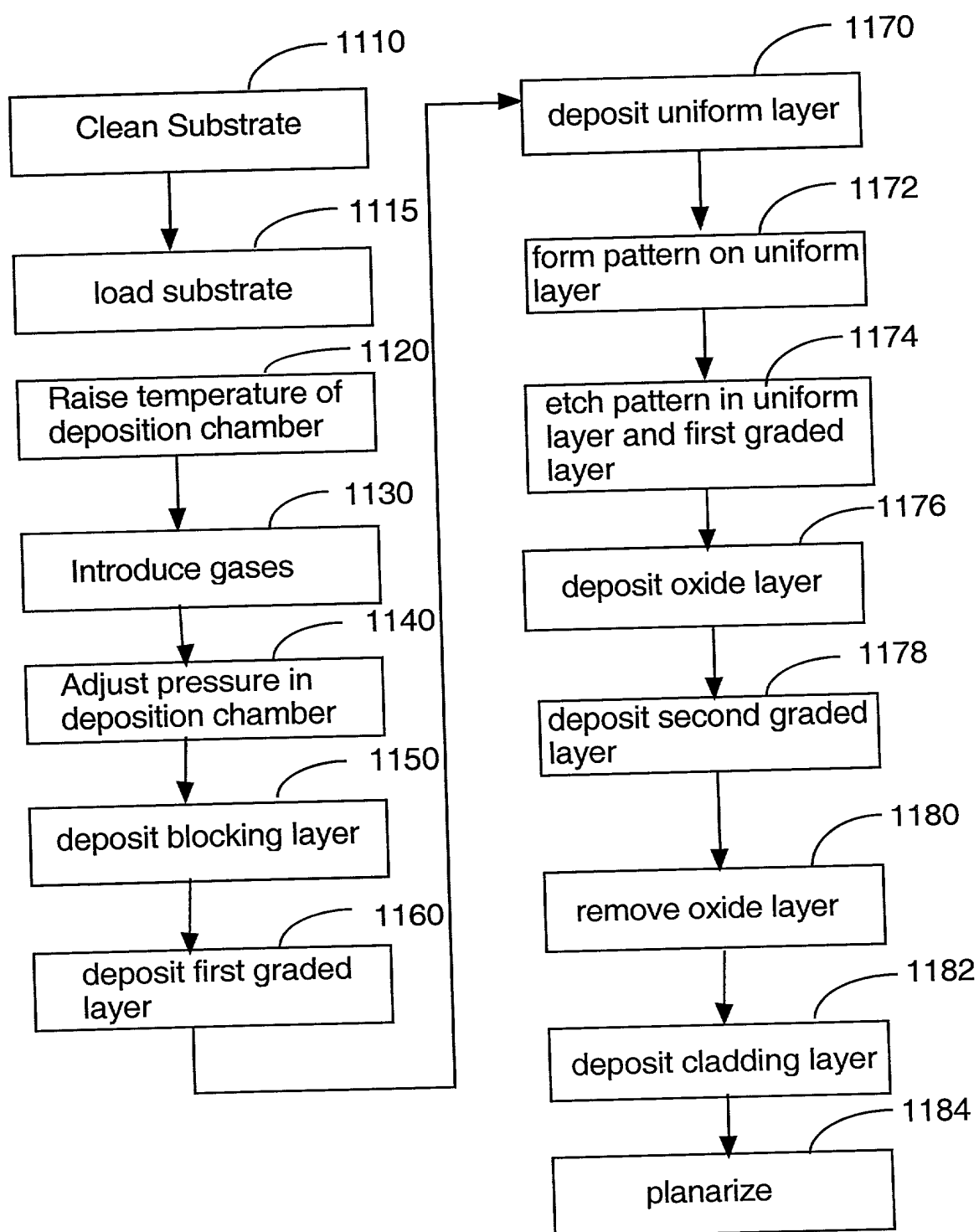


Figure 10

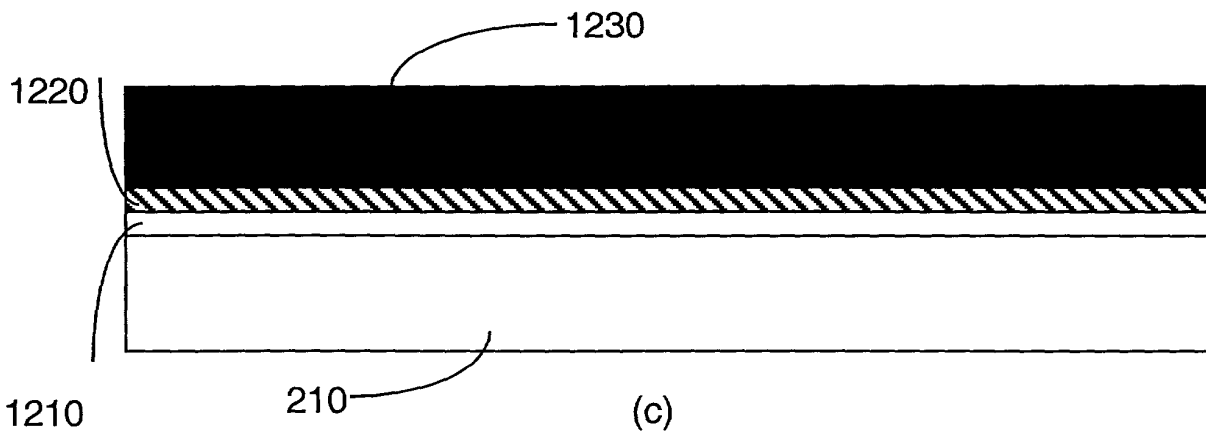
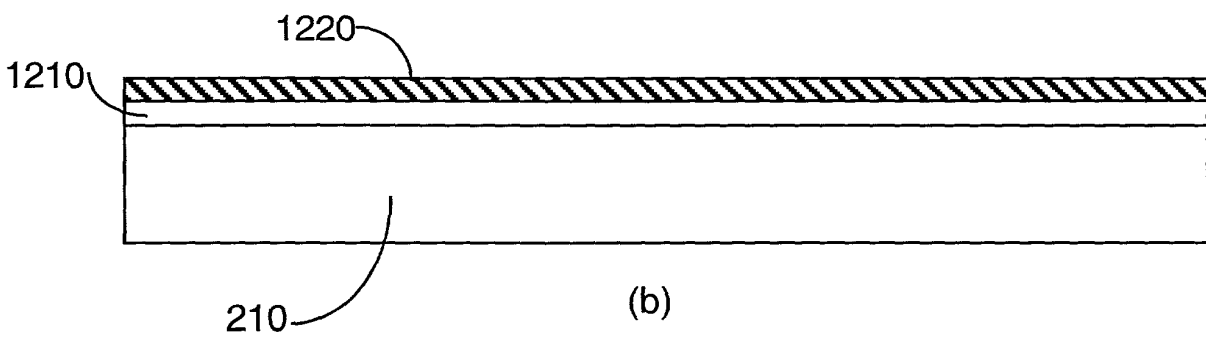
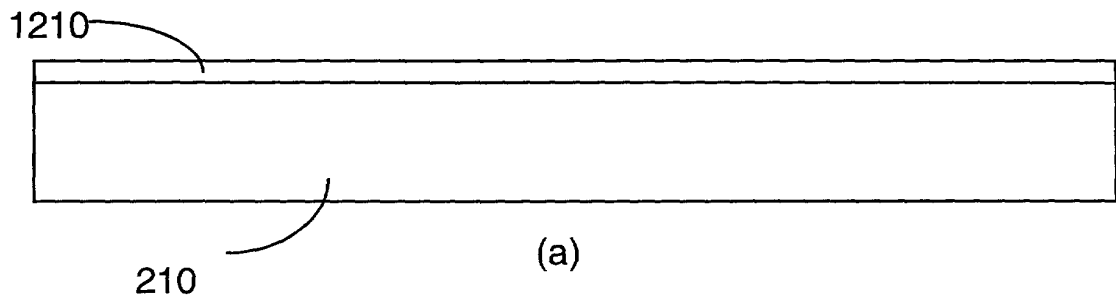


Figure 11

15/18

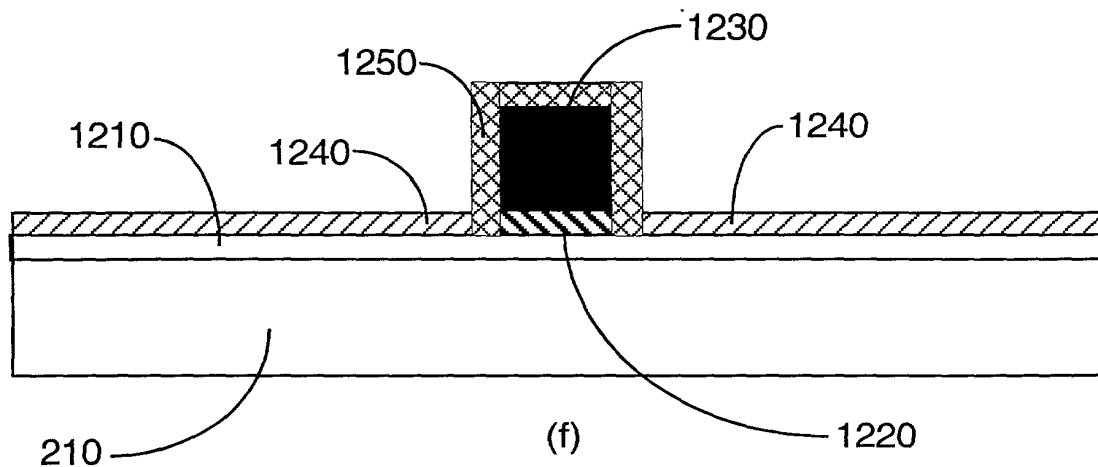
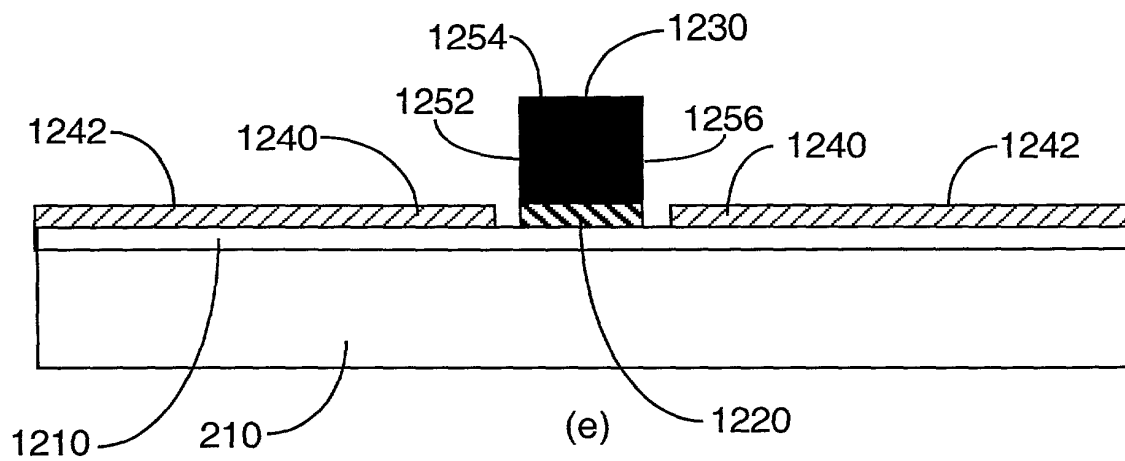
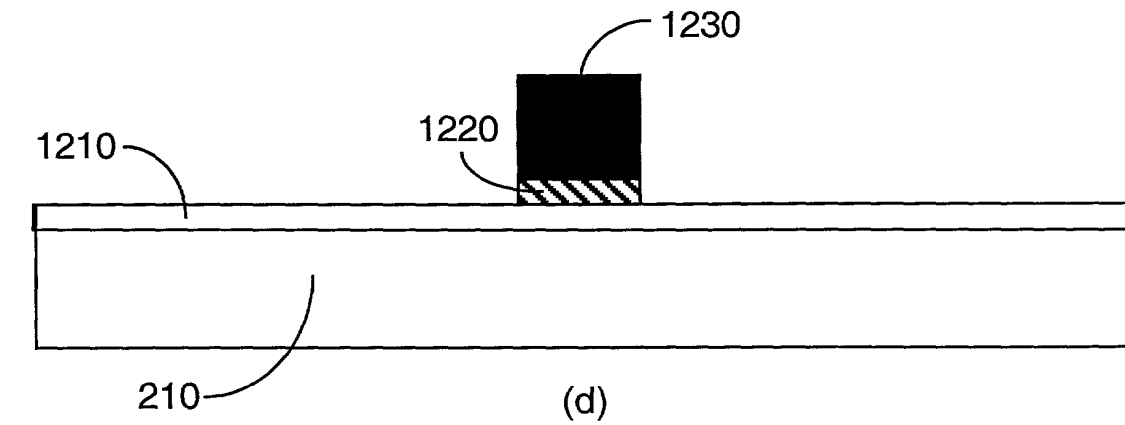


Figure 11

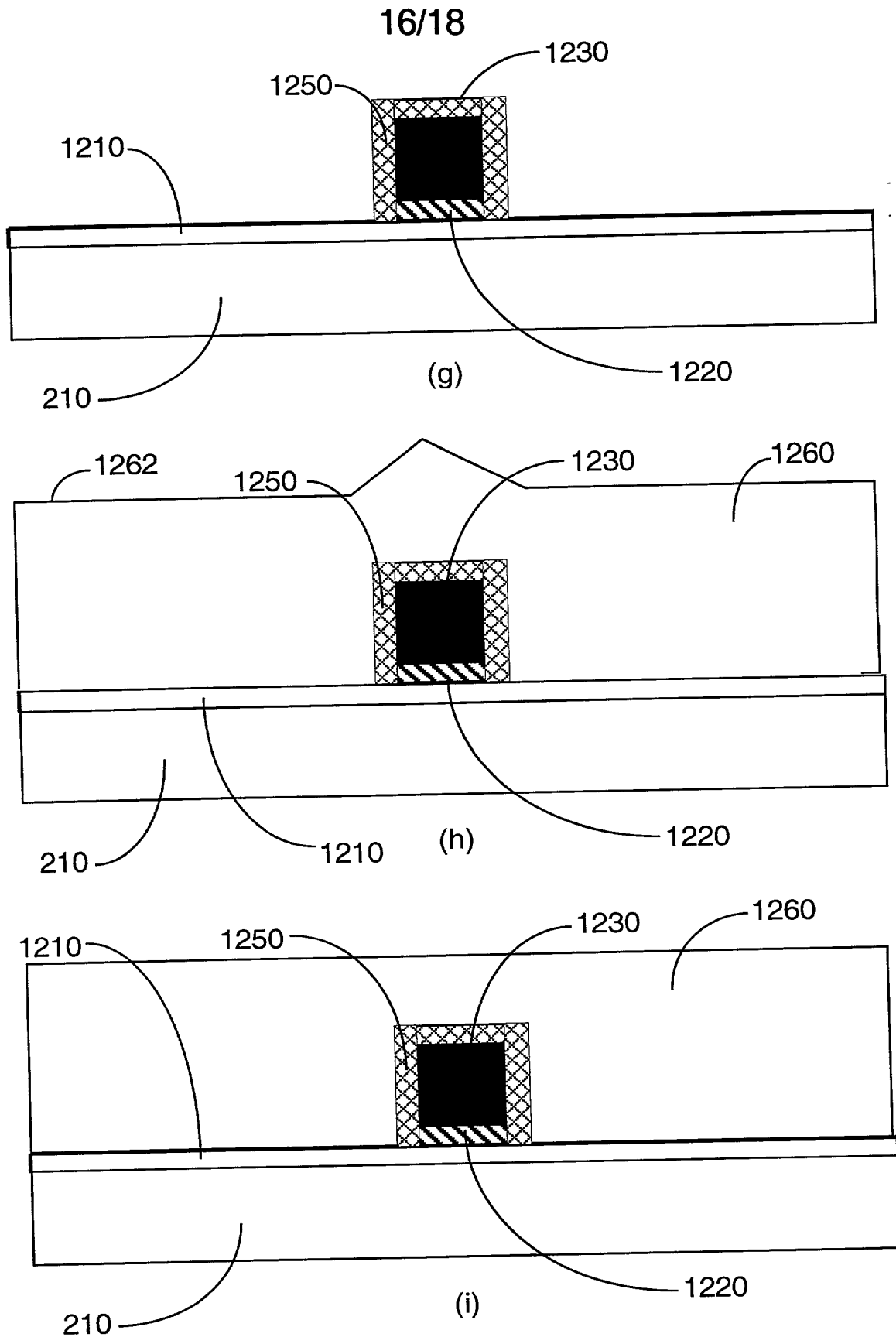


Figure 11



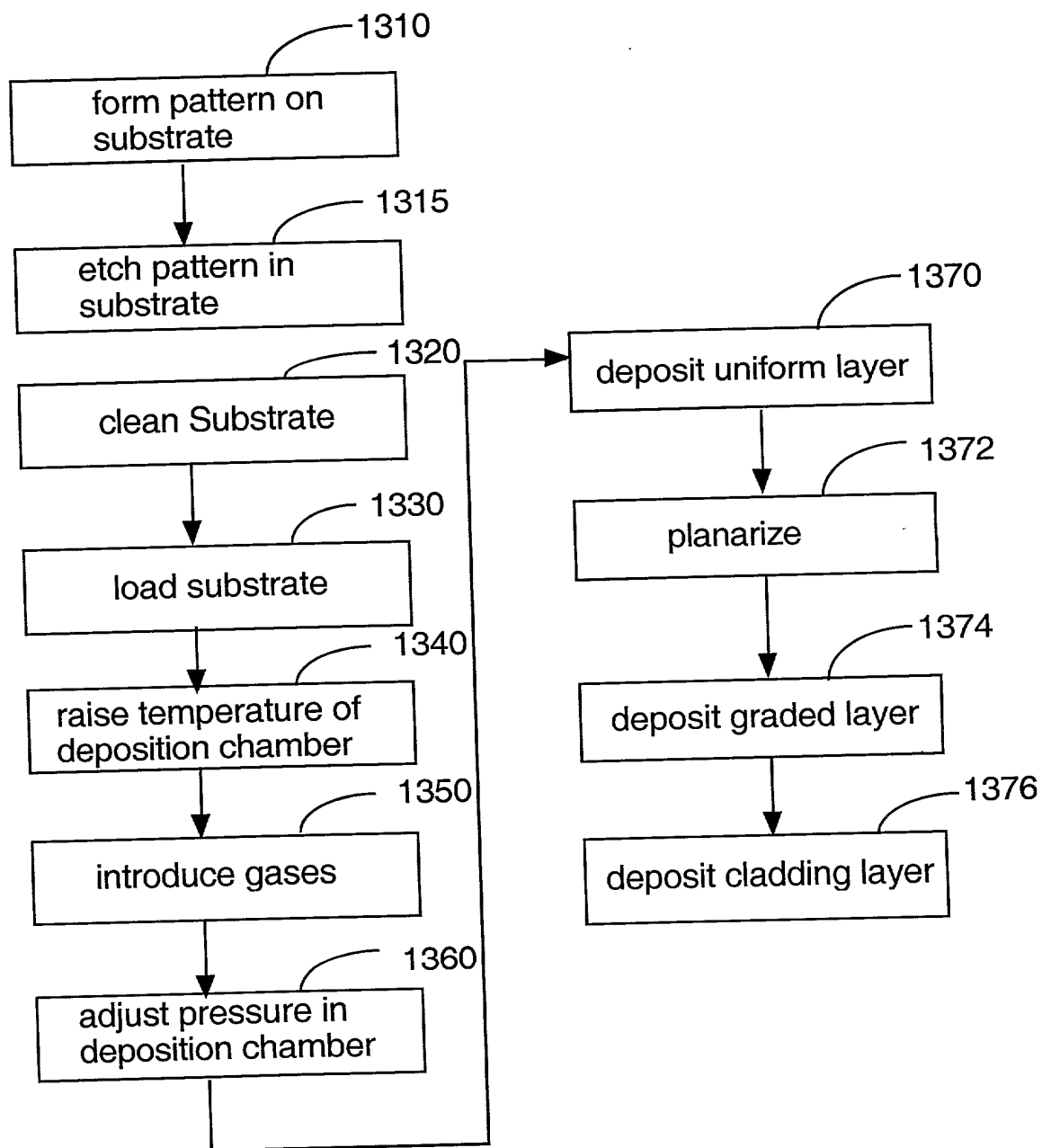


Figure 12

18/18

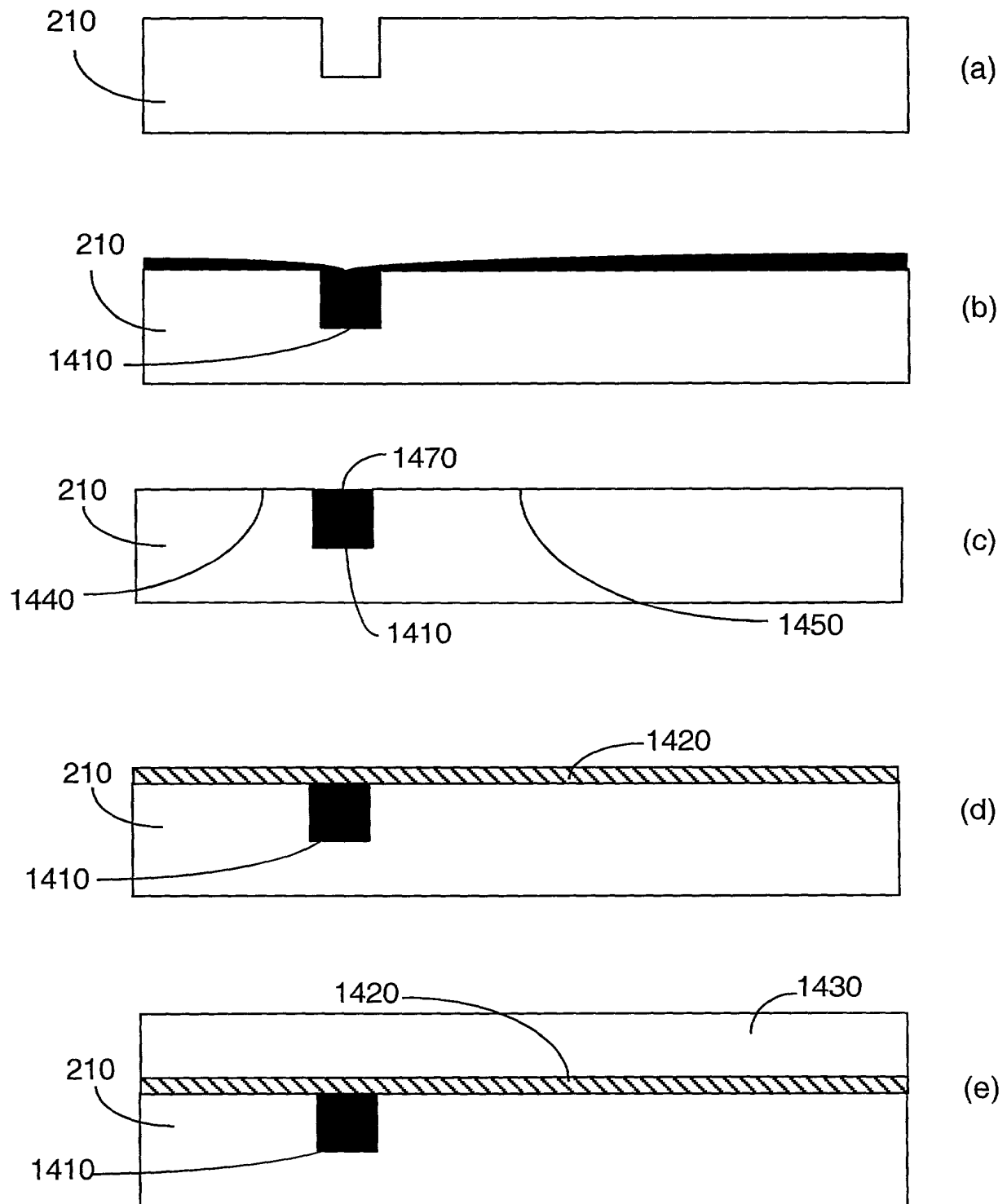


Figure 13